

WHAT IS CLAIMED IS:

1. An electrical test probe tip, comprising:
 - (a) a conductive flexible coil having a first end and a second end;
 - 5 (b) said first end for coupling with a device to be probed; and
 - (c) a connector attached to said second end of said conductive flexible coil.
- 10 2. The electrical test probe tip of claim 1, said connector being a connecting pin coupleable to a probing head.
3. The electrical test probe tip of claim 1, said connector being a square pin coupleable to a probing head.
- 15 4. The electrical test probe tip of claim 1, said connector being in integral connection with a probing head.
5. The electrical test probe tip of claim 1, said flexible coil having a longitudinal axis and a first diameter, said first diameter being substantially equal
20 throughout said longitudinal axis of said flexible coil.
6. The electrical test probe tip of claim 5, said first end having a second diameter larger than said first diameter.

7. The electrical test probe tip of claim 1, said first end further comprising a hook.

5 8. The electrical test probe tip of claim 1, said first end further comprising a foot.

9. The electrical test probe tip of claim 1 further comprising an exterior conductive sheath at least partially surrounding said conductive flexible coil.

10 10. The electrical test probe tip of claim 1 further comprising an exterior insulating sheath at least partially surrounding said conductive flexible coil.

15 11. The electrical test probe tip of claim 1 further comprising a conductor disposed at least partially through the axial center of said conductive flexible coil.

12. The electrical test probe tip of claim 11, wherein said conductor is made of a conductive elastomer.

20 13. A multipurpose electrical test probe tip, comprising:
(a) a conductive flexible member;
(b) said flexible member having a first end and a second end;
(c) said flexible member being substantially hollow at said first end;
and

- (d) said first end of said conductive flexible member for flexibly coupling with a component to be probed.

14. The multipurpose electrical test probe tip of claim 13, wherein said
5 second end of said conductive flexible member is interconnectable with a probing head.

15. The multipurpose electrical test probe tip of claim 14, wherein said second end of said conductive flexible member is integral with said probing head.

10 16. The multipurpose electrical test probe tip of claim 14, said second end of said conductive flexible member further comprising a connector coupleable with said probing head.

15 17. The multipurpose electrical test probe tip of claim 13, said flexible member having a longitudinal axis and a first diameter, said first diameter being substantially equal throughout said longitudinal axis of said flexible coil.

18. The multipurpose electrical test probe tip of claim 17, said first end having a second diameter larger than said first diameter.

20 19. The multipurpose electrical test probe tip of claim 13, said first end further comprising a hook.

25 20. The multipurpose electrical test probe tip of claim 13, said first end further comprising a foot.

21. The multipurpose electrical test probe tip of claim 1 further comprising an exterior conductive sheath at least partially surrounding said conductive flexible member.

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22. The multipurpose electrical test probe tip of claim 1 further comprising an exterior insulating sheath at least partially surrounding said conductive flexible member.

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23. The multipurpose electrical test probe tip of claim 1 further comprising a conductor disposed at least partially through the axial center of said conductive flexible member.

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24. A method for using a multipurpose electrical test probe having a probing head, said method comprising the steps of:

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- (a) providing a flexible spring tip, said flexible spring tip having a connector end connectable to said probing head and a flexible coil contact end remote from said probing head;
- (b) connecting said connector end to said probing head; and
- (c) placing said contact end in flexible electrical contact with an electrical component to be probed.

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25. The method of claim 24, wherein said step of connecting said connector end to said probing head further comprises the step of permanently connecting said connector end to said probing head.

26. The method of claim 24 further comprising the step of flexing said flexible spring tip while said contact end is in flexible electrical contact with said electrical component so as to allow access to a nearby electrical component.

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27. The method of claim 24 further comprising the step of flexing said flexible spring tip while said contact end is in flexible electrical contact with said electrical component so as to allow access to a nearby ground component.